



10th European Test Symposium

Reval Hotel Olümpia, Tallinn, Estonia
May 22-25, 2005



Call for Papers

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Y. Zorian - Virage Logic (USA)

The IEEE European Test Symposium (ETS) is a well-recognized forum for presenting and discussing hot topics, trends, emerging results, and practical applications in the area of electronic-based circuit and system testing.

The 2005 edition of the symposium will take place in Tallinn, whose beautiful Old Town with its fascinating medieval architecture and slender church spires is included in the UNESCO World Heritage list.

ETS'05 will be co-sponsored by the IEEE Computer Society – Test Technology Technical Council (TTTC) and the Tallinn University of Technology.

We cordially invite you to participate and submit your contributions to ETS'05, which includes (but is not limited to) the following topics:

- Analog, Mixed-Signal, RF Test
- ATE Hardware and Software
- ATPG and High-Level TPG
- Current based testing
- Debug and Diagnosis
- Defect/Fault Tolerance and Reliability
- Design Verification/Validation
- Emerging Testability Standards
- Failure Analysis, Defect and Fault Modeling
- Fault Simulation
- FPGA Test
- High-Level DfT
- Low-Cost Testers
- Memory and Processor Test
- MEMS Testing
- On-Line and Off-Line BIST
- Power issues in testing
- Scan-Based Techniques and Boundary Scan
- Self-Repair Methodologies
- Signal Integrity Test
- System Test
- Test of Embedded Cores and System-on-Chip
- Test of MCMs and Boards
- Test Resource Partitioning and Embedded Test
- Test Synthesis and Synthesis for Testability
- Yield Analysis and Enhancement

Submissions - ETS'05 seeks for several types of contributions, including *Research Contributions, Application Contributions, Emerging Ideas Contributions, PhD student forum Contributions, ...*

Review criteria and publication policy are posted at the web page <http://www.ttu.ee/ati/ETS>. Electronic submission of PDF files via this www page is required.

Proceedings - *Formal proceedings* of selected papers published by the IEEE Computer Society and *informal proceedings* will be distributed to every participant, during the Symposium.

Key Dates

- Submission deadline: **December 10th, 2004**
- Notification of acceptance: **February 10th, 2005**
- Camera ready: **March 12th, 2005**



IEEE TTTC Test Technology Educational Program (TTEP)

TTEP tutorials will be offered during May 22 on emerging test technology topics. Tutorial proposals should be submitted according to the guidelines given at <http://tab.computer.org/ttcc/tegep>.

Further Information

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Visit the ETS web page at: <http://www.lirmm.fr/ETS/>

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